

2nd generation thinQ!TM SiC Schottky Diode

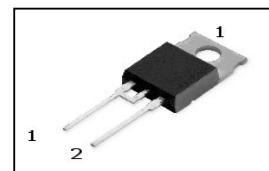
Features

- Revolutionary semiconductor material - Silicon Carbide
- Switching behavior benchmark
- No reverse recovery/ No forward recovery
- No temperature influence on the switching behavior
- High surge current capability
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC¹⁾ for target applications
- Breakdown voltage tested at 5mA²⁾

Product Summary

| | | |
|----------|-----|----|
| V_{DC} | 600 | V |
| Q_c | 15 | nC |
| I_F | 6 | A |

PG-T0220-2-2



thinQ! 2G Diode specially designed for fast switching applications like:

- CCM PFC
- Motor Drives

| Type | Package | | Marking | Pin 1 | Pin 2 |
|-----------|--------------|--|---------|-------|-------|
| IDT06S60C | PG-T0220-2-2 | | D06S60C | C | A |

Maximum ratings, at $T_j=25$ °C, unless otherwise specified

| Parameter | Symbol | Conditions | Value | Unit |
|---|----------------|--|-------------|------------------|
| Continuous forward current | I_F | $T_C < 140$ °C | 6 | A |
| RMS forward current | $I_{F,RMS}$ | $f=50$ Hz | 9 | |
| Surge non-repetitive forward current, sine halfwave | $I_{F,SM}$ | $T_C = 25$ °C, $t_p = 10$ ms | 49 | |
| Repetitive peak forward current | $I_{F,RM}$ | $T_j = 150$ °C, $T_C = 100$ °C, $D = 0.1$ | 28 | |
| Non-repetitive peak forward current | $I_{F,max}$ | $T_C = 25$ °C, $t_p = 10$ µs | 210 | |
| i^2t value | $\int i^2 dt$ | $T_C = 25$ °C, $t_p = 10$ ms | 12 | A ² s |
| Repetitive peak reverse voltage | V_{RRM} | | 600 | V |
| Diode ruggedness dv/dt | dv/dt | $V_R = 0 \dots 480$ V | 50 | V/ns |
| Power dissipation | P_{tot} | $T_C = 25$ °C | 63 | W |
| Operating and storage temperature | T_j, T_{stg} | | -55 ... 175 | °C |
| Mounting torque | | M3 and M3.5 screws | 60 | Ncm |

| Parameter | Symbol | Conditions | Values | | | Unit |
|-----------|--------|------------|--------|------|------|------|
| | | | min. | typ. | max. | |

Thermal characteristics

| | | | | | | |
|---|------------|------------------------------------|---|---|-----|-----|
| Thermal resistance, junction - case | R_{thJC} | | - | - | 2.4 | K/W |
| Thermal resistance, junction - ambient | R_{thJA} | leaded | - | - | 62 | |
| Soldering temperature, wave soldering only allowed al leads | T_{sold} | 1.6mm(0.063 in.) from case for 10s | - | - | 260 | °C |

Electrical characteristics, at $T_j=25$ °C, unless otherwise specified

Static characteristics

| | | | | | | |
|-----------------------|----------|---------------------------|-----|-----|-----|----|
| DC blocking voltage | V_{DC} | $I_R=0.08$ mA | 600 | - | - | V |
| Diode forward voltage | V_F | $I_F=6$ A, $T_j=25$ °C | - | 1.5 | 1.7 | |
| | | $I_F=6$ A, $T_j=150$ °C | - | 1.7 | 2.1 | |
| Reverse current | I_R | $V_R=600$ V, $T_j=25$ °C | - | 0.7 | 80 | μA |
| | | $V_R=600$ V, $T_j=150$ °C | - | 3 | 800 | |

AC characteristics

| | | | | | | |
|------------------------------|-------|--|---|-----|-----|----|
| Total capacitive charge | Q_c | $V_R=400$ V, $I_F \leq I_{F,max}$, $di_F/dt=200$ A/μs, | - | 15 | - | nC |
| Switching time ³⁾ | t_c | $T_j=150$ °C | - | - | <10 | |
| | | | - | - | - | |
| Total capacitance | C | $V_R=1$ V, $f=1$ MHz | - | 280 | - | pF |
| | | $V_R=300$ V, $f=1$ MHz | - | 35 | - | |
| | | $V_R=600$ V, $f=1$ MHz | - | 35 | - | |

¹⁾ J-STD20 and JESD22

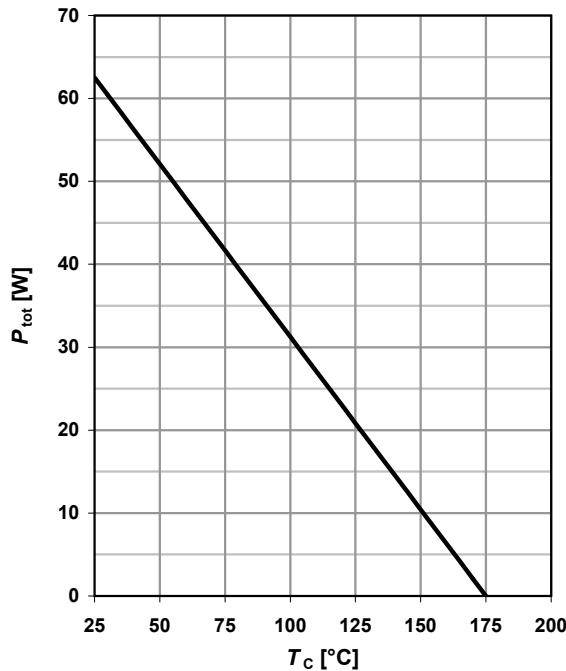
²⁾ All devices tested under avalanche conditions, for a time period of 5ms at 5mA.

³⁾ t_c is the time constant for the capacitive displacement current waveform (independent from T_j , I_{LOAD} and di/dt), different from t_{rr} , which is dependent on T_j , I_{LOAD} , di/dt . No reverse recovery time constant t_{rr} due to absence of minority carrier injection.

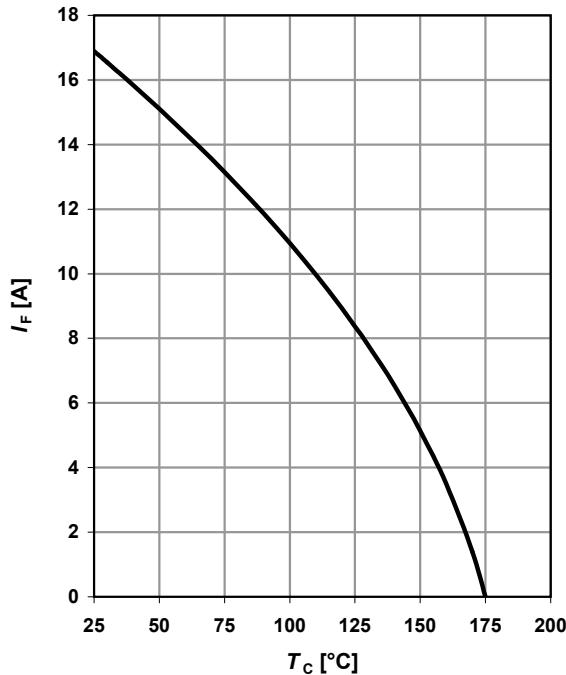
⁴⁾ Only capacitive charge occurring, guaranteed by design.

1 Power dissipation

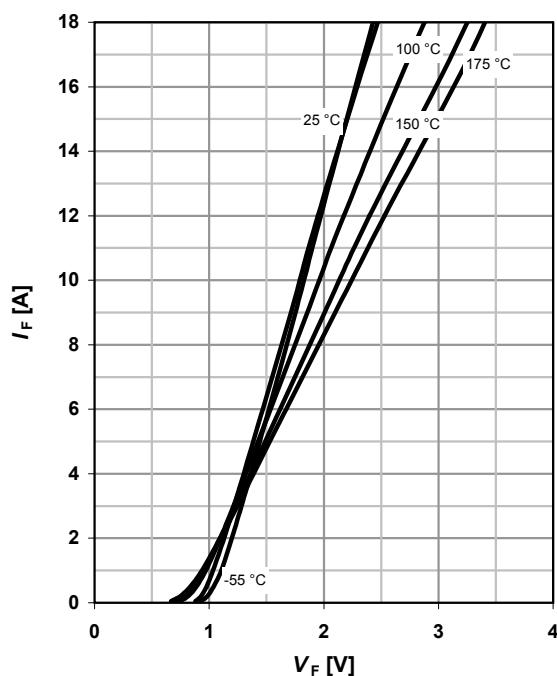
$$P_{\text{tot}} = f(T_c)$$

 parameter: $R_{\text{thJC(max)}}$

2 Diode forward current

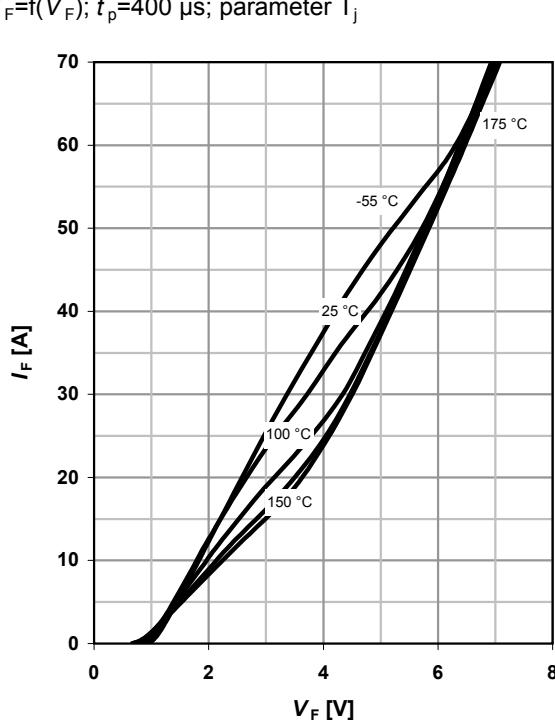
$$I_F = f(T_c); T_j \leq 175 \text{ °C}$$

 parameter: $R_{\text{thJC(max)}}; V_{F(\text{max})}$

3 Typ. forward characteristic

$$I_F = f(V_F); t_p = 400 \mu\text{s}$$

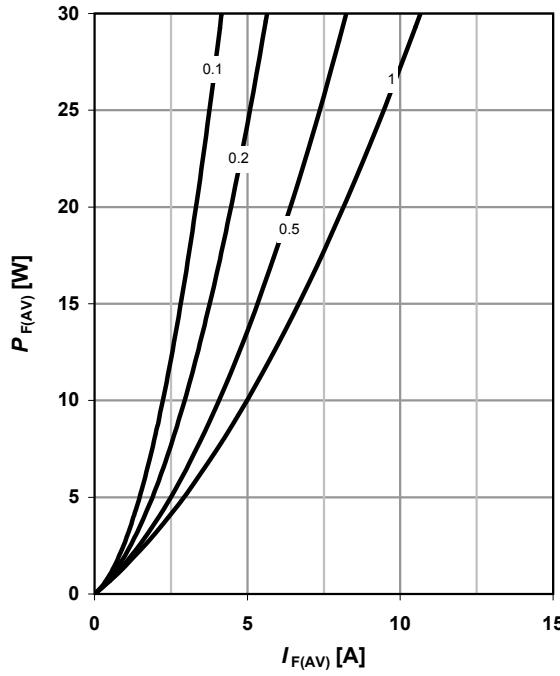
 parameter: T_j

4 Typ. forward characteristic in surge current mode

$$I_F = f(V_F); t_p = 400 \mu\text{s}; \text{parameter } T_j$$



**5 Typ. forward power dissipation vs.
average forward current**

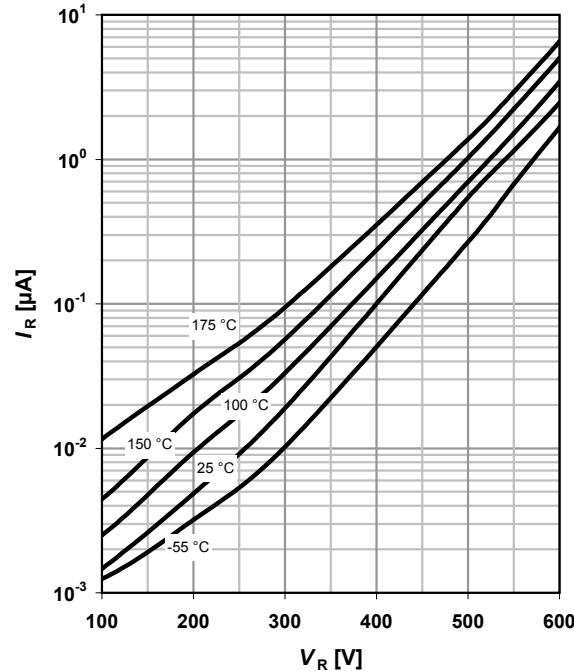
$P_{F,AV}=f(I_F)$, $T_C=100\text{ }^\circ\text{C}$, parameter: $D=t_p/T$



6 Typ. reverse current vs. reverse voltage

$I_R=f(V_R)$

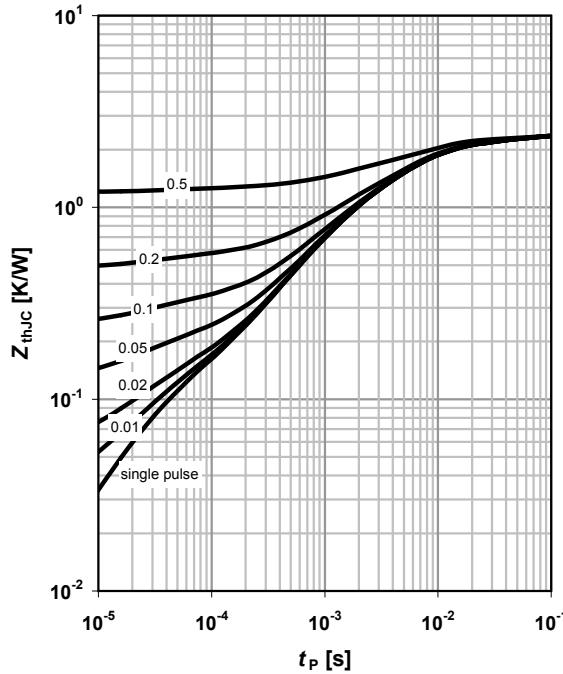
parameter: T_j



7 Transient thermal impedance

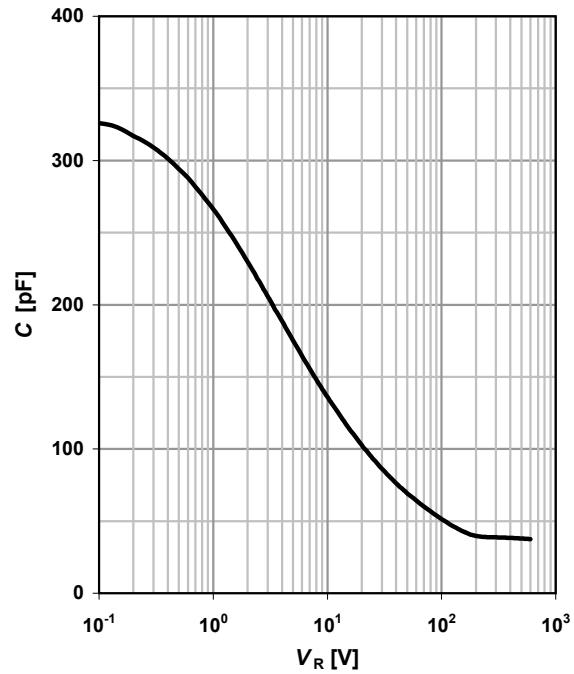
$Z_{thJC}=f(t_p)$

parameter: $D=t_p/T$



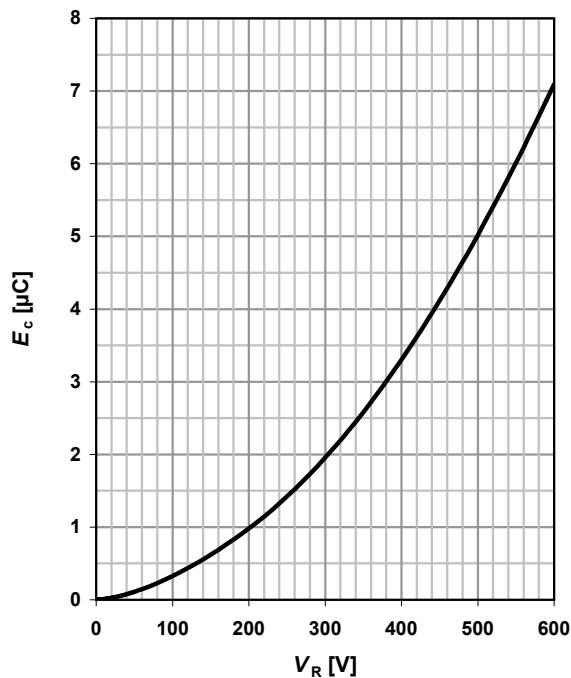
8 Typ. capacitance vs. reverse voltage

$C=f(V_R)$; $T_C=25\text{ }^\circ\text{C}$, $f=1\text{ MHz}$

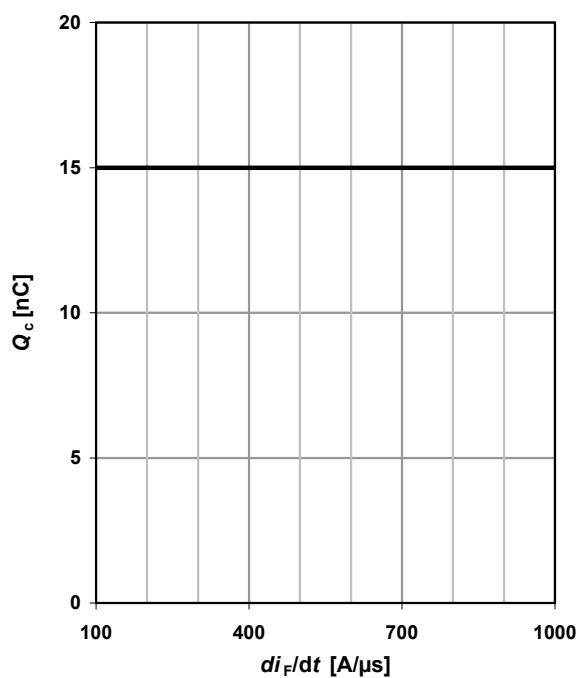


9 Typ. C stored energy

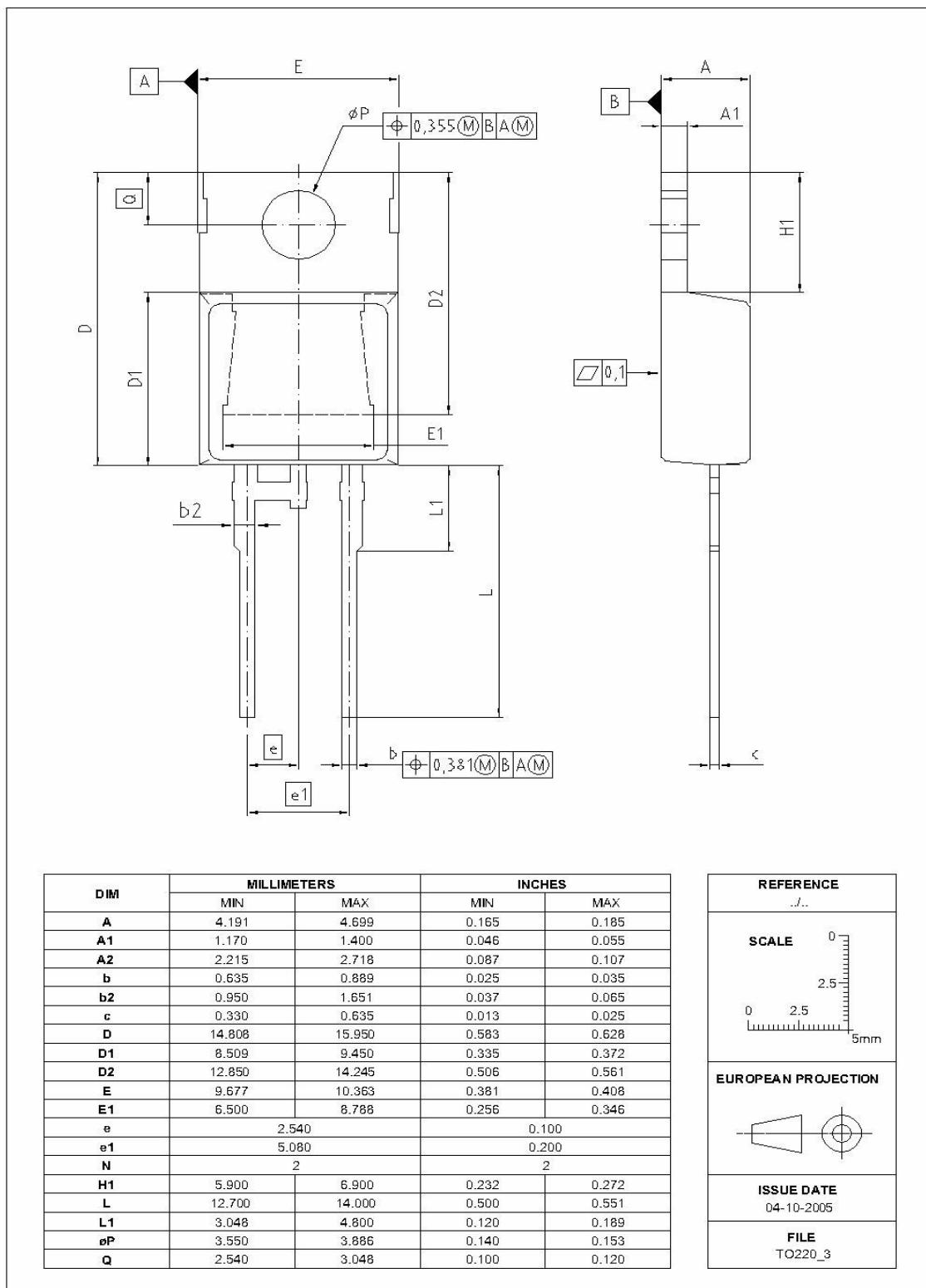
$$E_C = f(V_R)$$


10 Typ. capacitance charge vs. current slope

$$Q_C = f(di_F/dt)^{4/3}, \quad T_J = 150^\circ\text{C}; \quad i_F \leq i_{F,\max}$$



PG-T0220-2-2: Outline



Dimensions in mm/inches

Published by
Infineon Technologies AG
81726 München, Germany

© Infineon Technologies AG 2006.
All Rights Reserved.

Attention please!

The information herein is given to describe certain components and shall not be considered as warranted characteristics.

Terms of delivery and rights to technical change reserved.

We hereby disclaim any and all warranties, including but not limited to warranties of non-infringement, regarding circuits, descriptions and charts stated herein.

Infineon Technologies is an approved CECC manufacturer.

Information

For further information on technology, delivery terms and conditions and prices, please contact your nearest Infineon Technologies office in Germany or our Infineon Technologies representatives worldwide (see address list).

Warnings

Due to technical requirements, components may contain dangerous substances.

For information on the types in question, please contact your nearest Infineon Technologies office.

Infineon Technologies' components may only be used in life-support devices or systems with the expressed written approval of Infineon Technologies if a failure of such components can reasonably be expected to cause the failure of that life-support device or system, or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body, or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.